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(12) United States Design Patent

Nakahara et al.

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(54) **X-RAY PRODUCTION APPARATUS FOR INSPECTION TOUR**

(75) Inventors: **Tadahiko Nakahara**, Kyoto (JP); **Hiroshi Miyata**, Kyoto (JP); **Toshiaki Nakamura**, Kyoto (JP); **Hiroshi Muraoka**, Kyoto (JP)

(73) Assignee: **Shimadzu Corporation**, Kyoto (JP)

(**) Term: **14 Years**

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(22) Filed: **Jun. 18, 2008**

(30) **Foreign Application Priority Data**

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Mar. 12, 2008	(JP)	2008-006084

(51) **LOC (9) Cl.** **24-01**
(52) **U.S. Cl.** **D24/158**
(58) **Field of Classification Search** D24/158–161, D24/183, 186; 378/4, 15, 17, 19, 20, 21–27, 378/38–40, 102, 146, 195, 197, 198; 600/409, 600/410, 425, 476
See application file for complete search history.

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Primary Examiner—T. Chase Nelson
Assistant Examiner—Anhdao Doan
(74) *Attorney, Agent, or Firm*—J.C. Patents

(57) **CLAIM**

The ornamental design for an X-ray production apparatus for inspection tour, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of an X-ray production apparatus for inspection tour showing the new design;

FIG. **2** is a front view of FIG. **1**;

FIG. **3** is a rear view of FIG. **1**;

FIG. **4** is a left side view of FIG. **1**;

FIG. **5** is a right side view of FIG. **1**;

FIG. **6** is a top view of FIG. **1**;

FIG. **7** is a bottom view of FIG. **1**;

FIG. **8** is another perspective reference view of FIG. **1** showing the new design in use;

FIG. **9** is a perspective view of an X-ray production apparatus for inspection tour showing another embodiment of the new design;

FIG. **10** is a front view of FIG. **9**;

FIG. **11** is a rear view of FIG. **9**;

FIG. **12** is a left side view of FIG. **9**;

FIG. **13** is a right side view of FIG. **9**;

FIG. **14** is a top view of FIG. **9**;

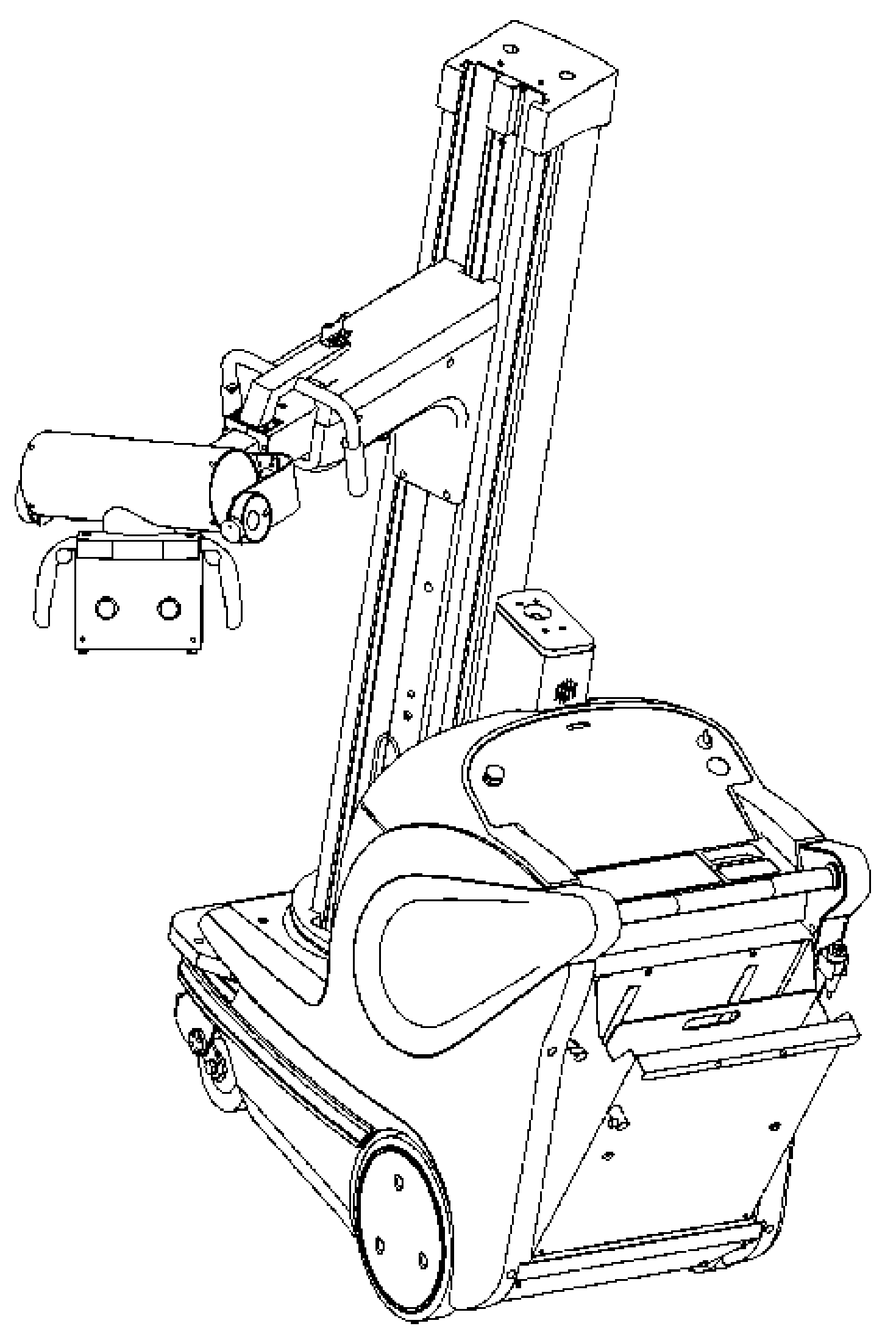
FIG. **15** is a bottom view of FIG. **9**;

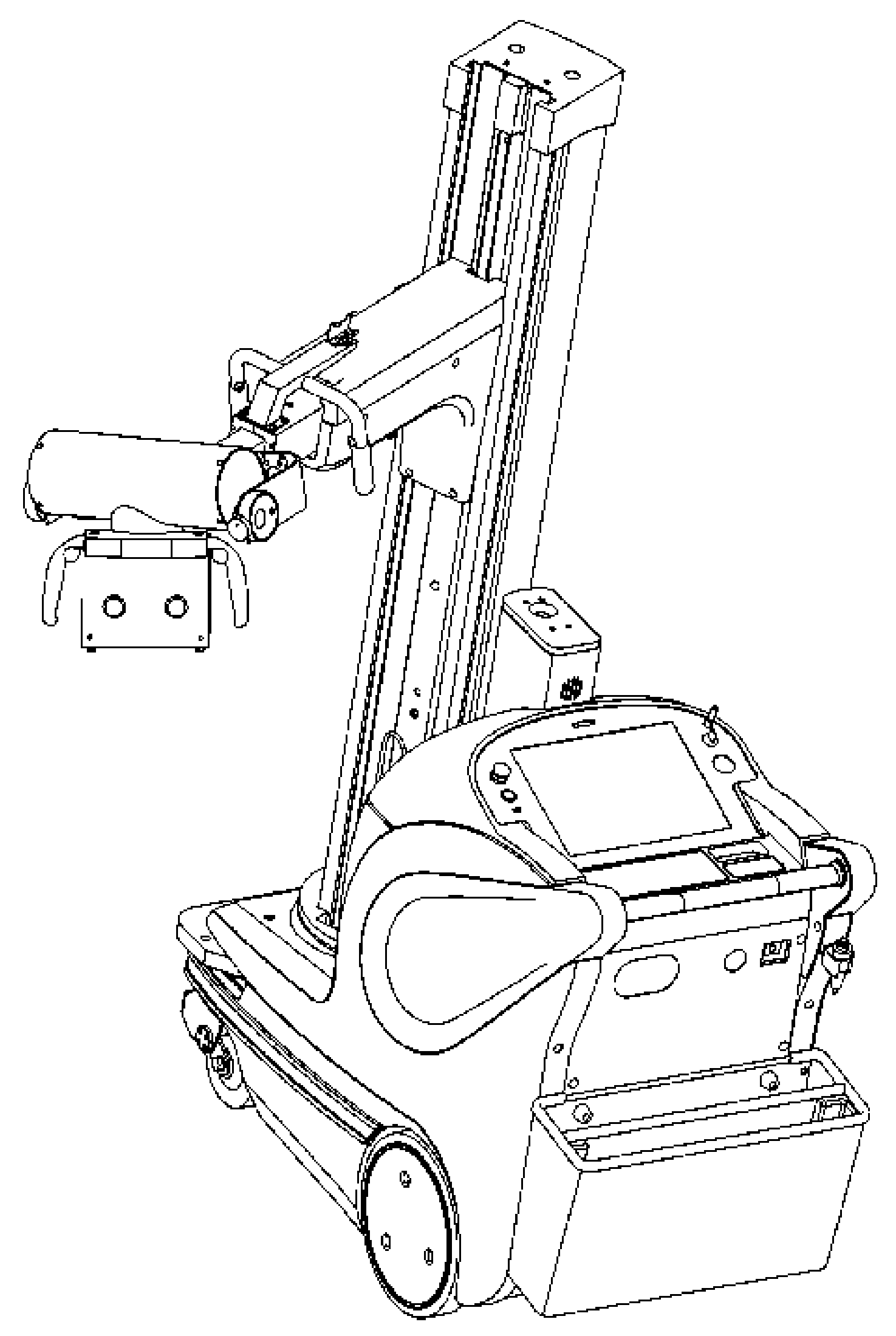
FIG. **16** is another perspective reference view of FIG. **9** showing the new design in use; and,

FIG. **17** is a partially enlarged view of FIG. **16**.

The portions of the X-ray production apparatus for inspection tour in broken lines in FIGS. **6**, **7**, **14** and **15** form no part of the claimed design.

1 Claim, 17 Drawing Sheets





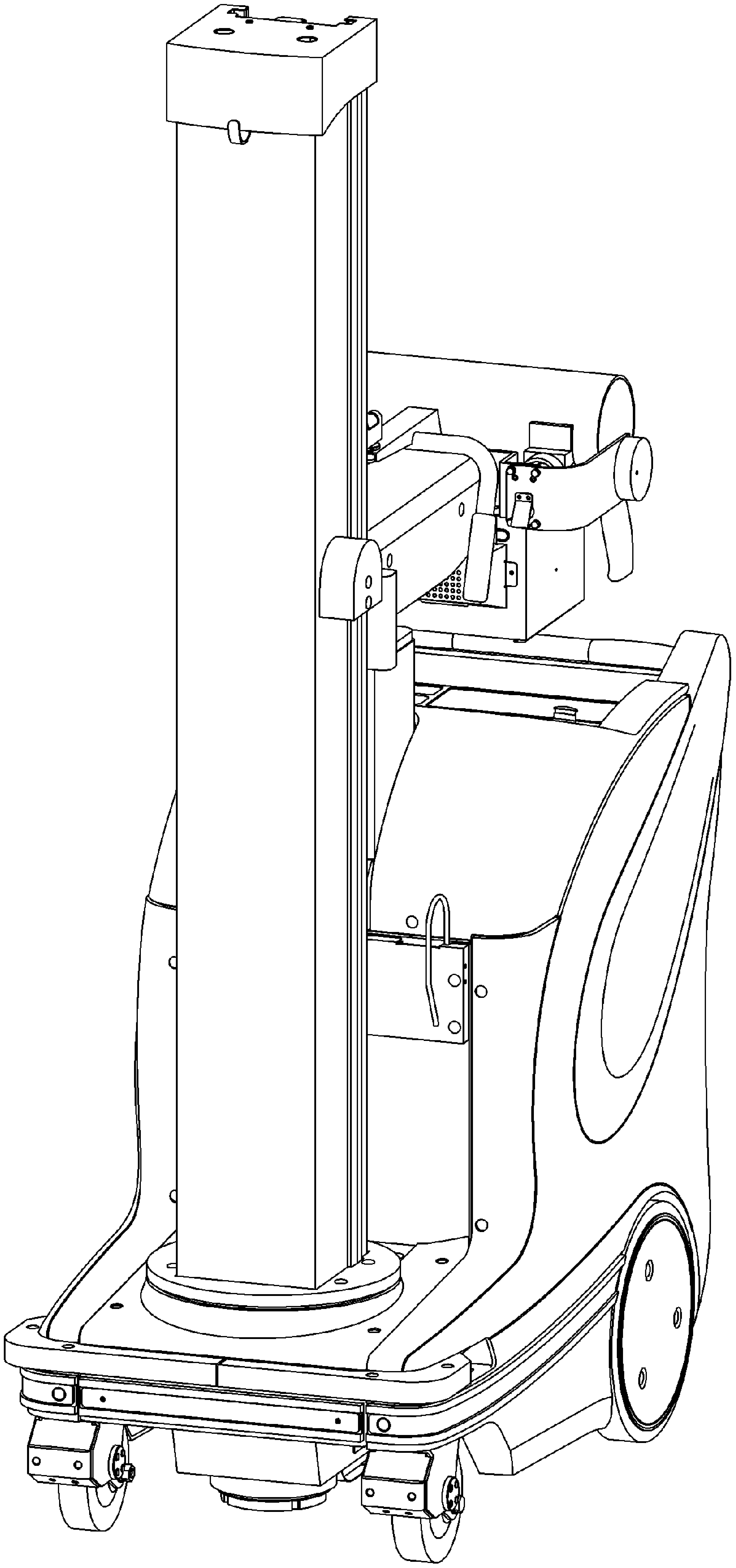


FIG. 1

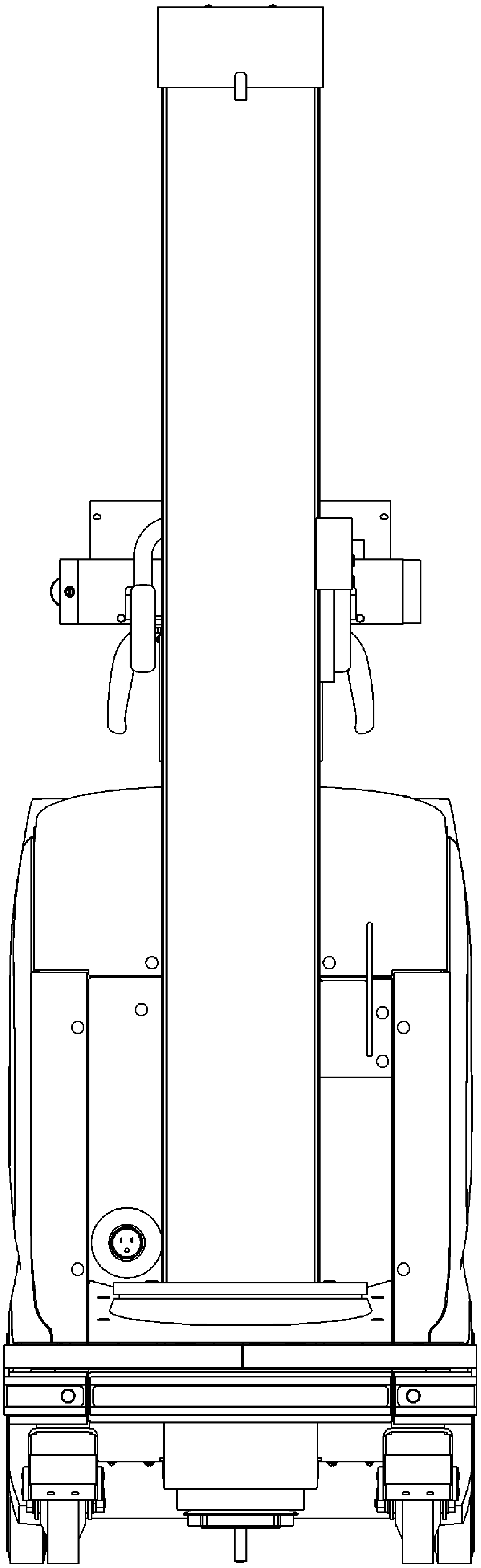


FIG. 2

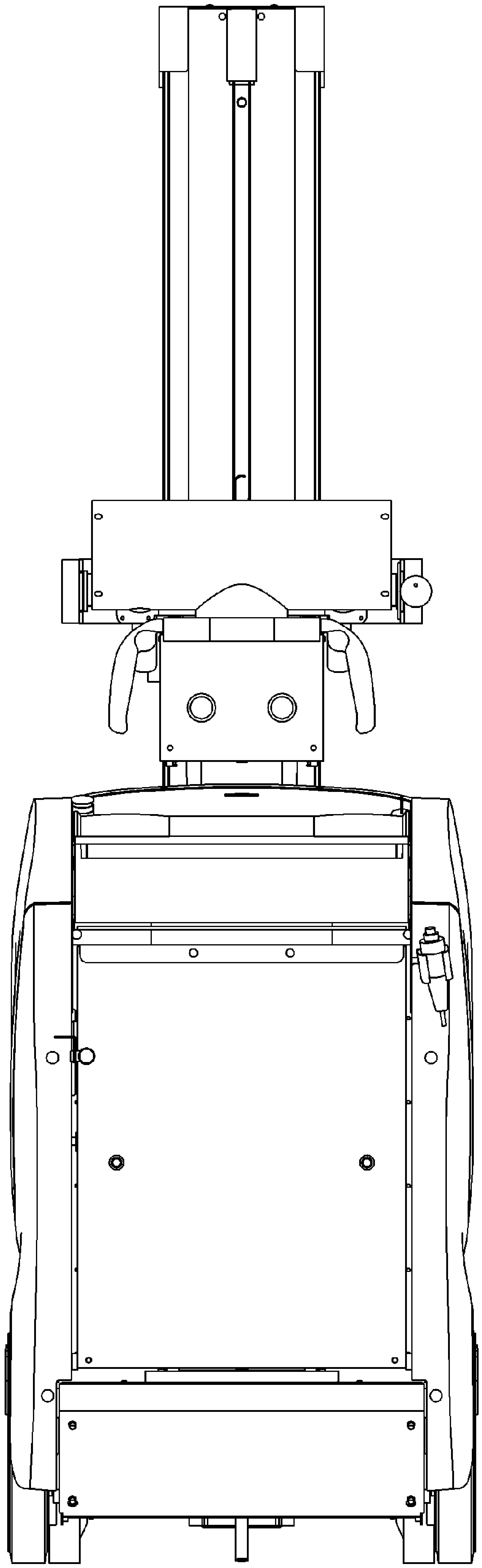


FIG. 3

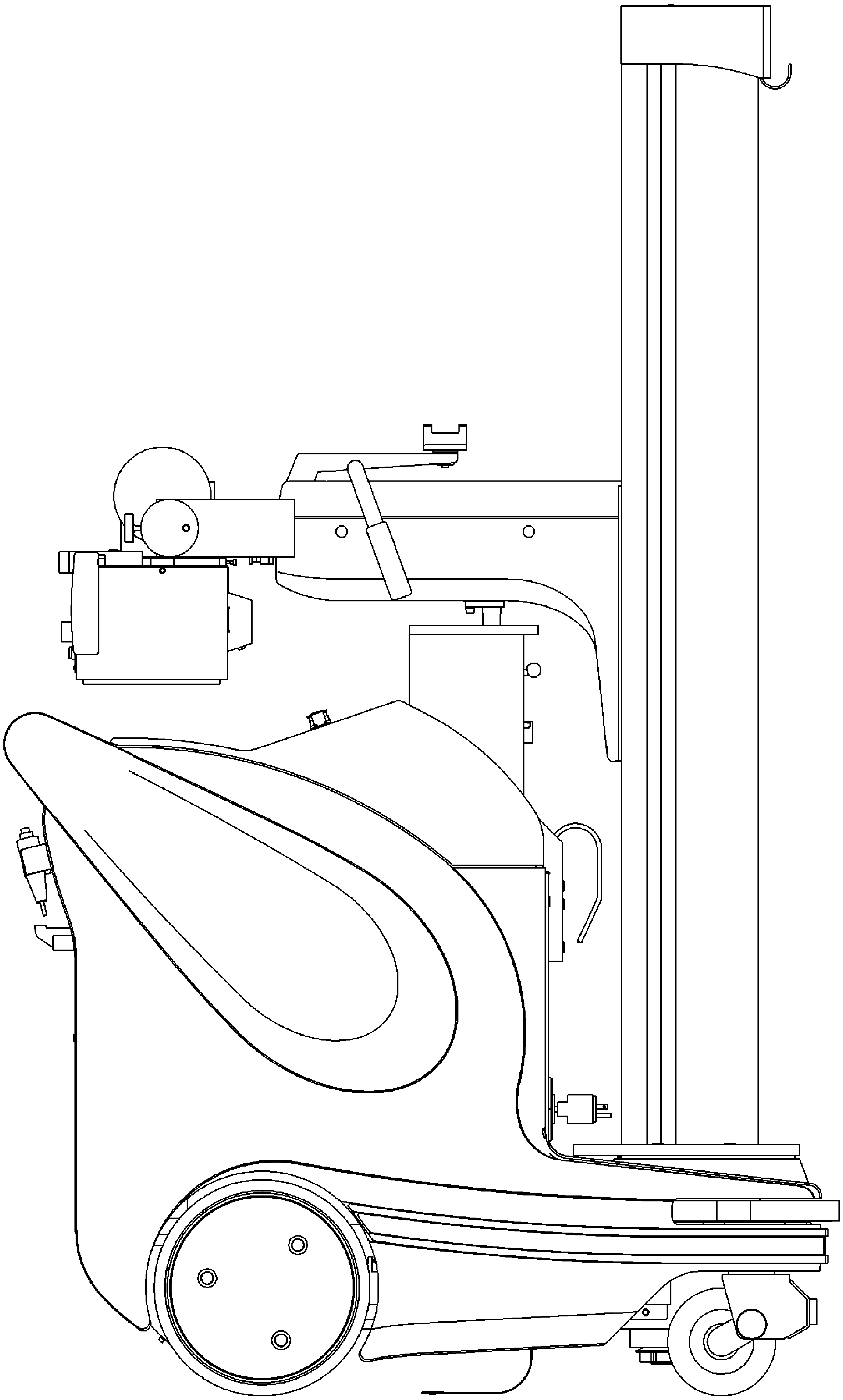


FIG. 4

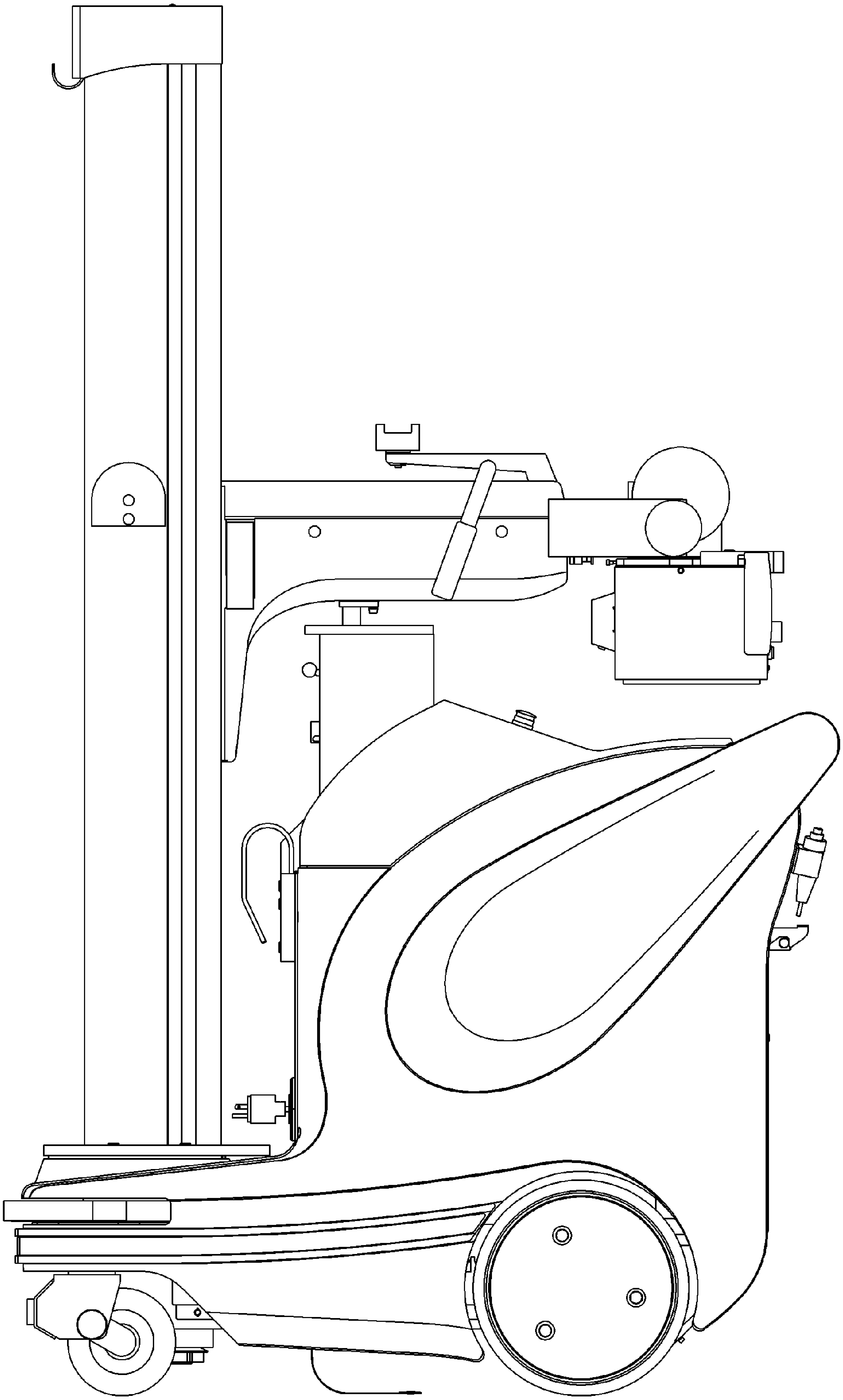


FIG. 5

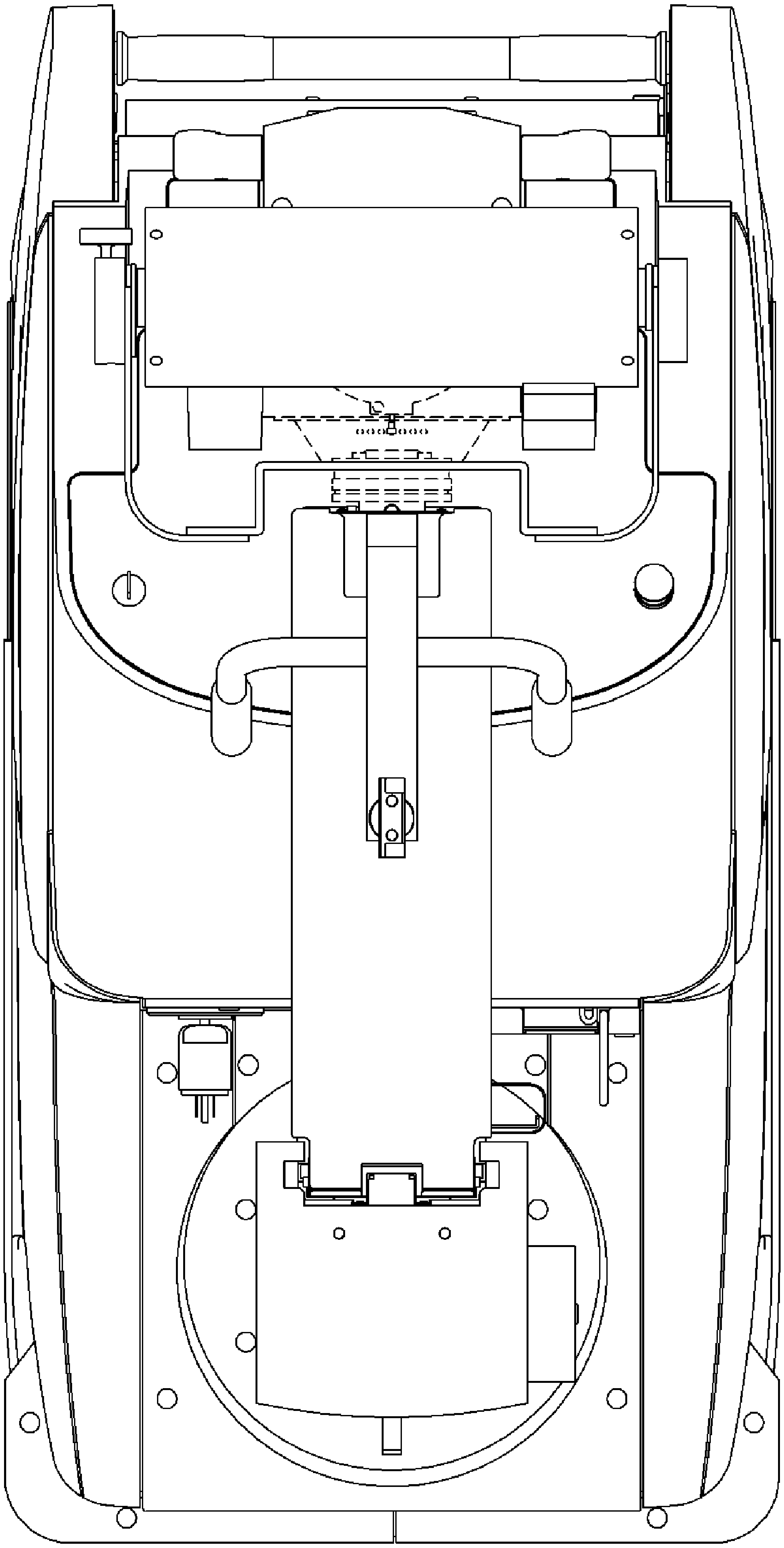


FIG. 6

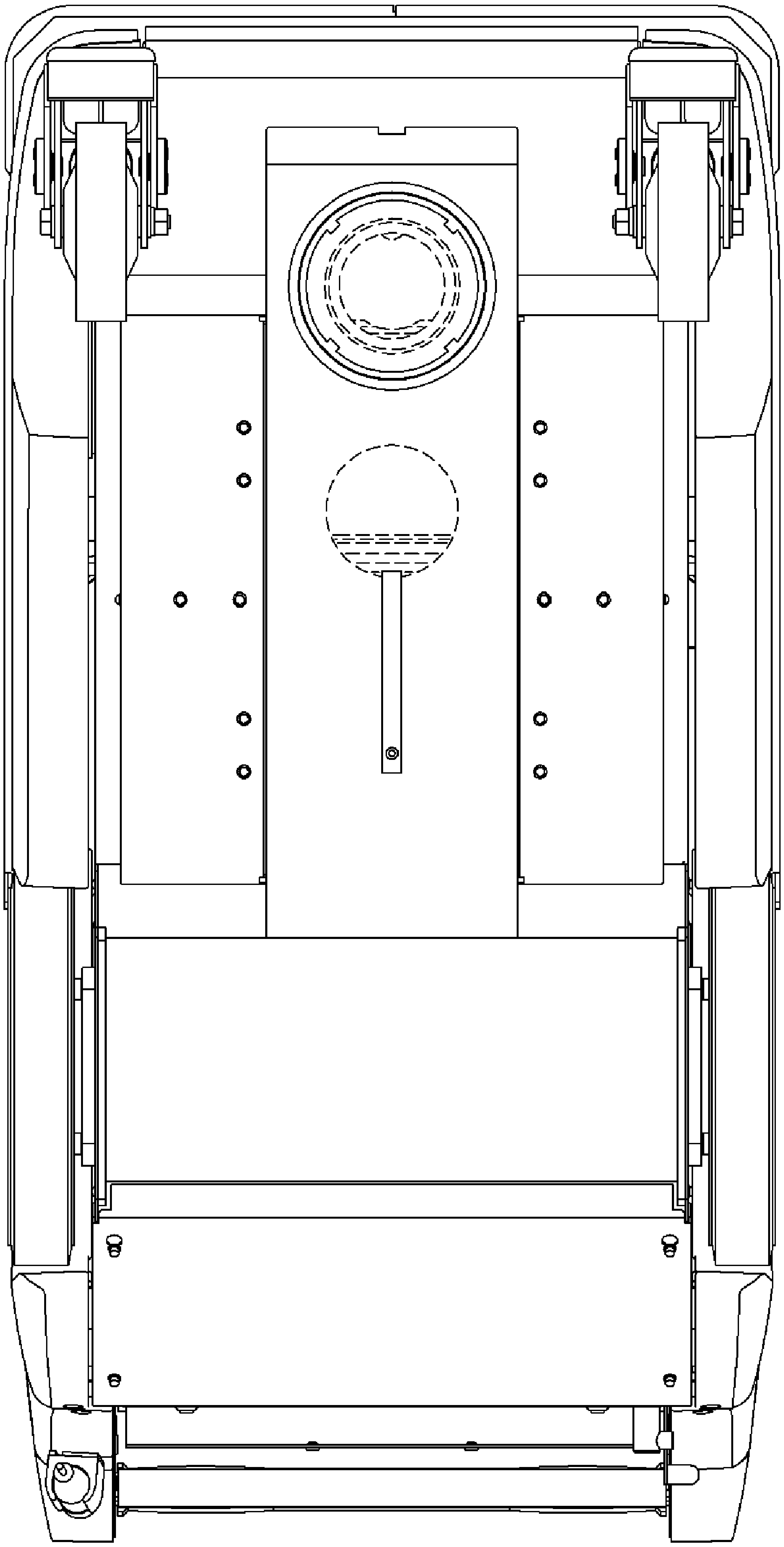


FIG. 7

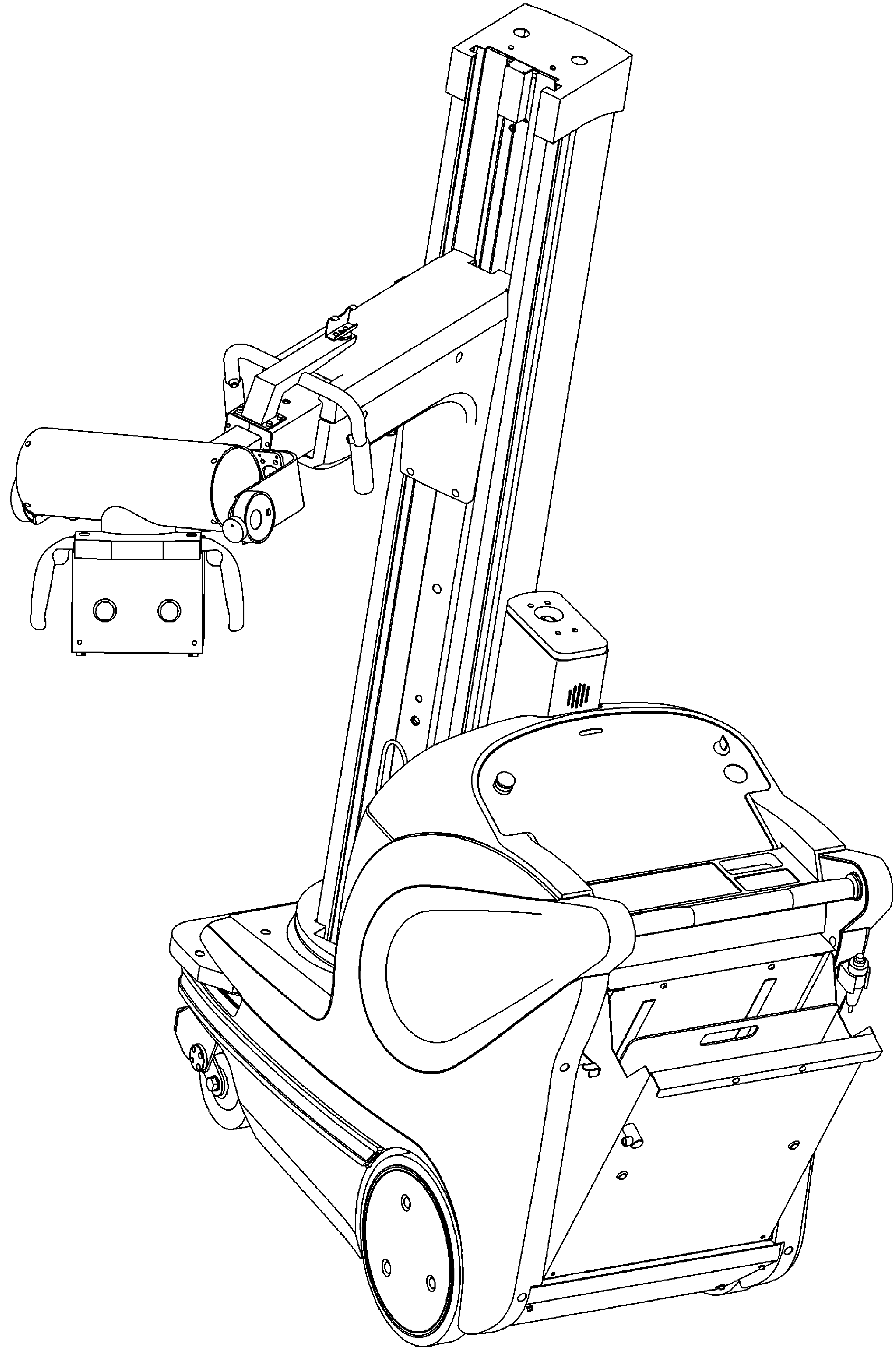


FIG. 8

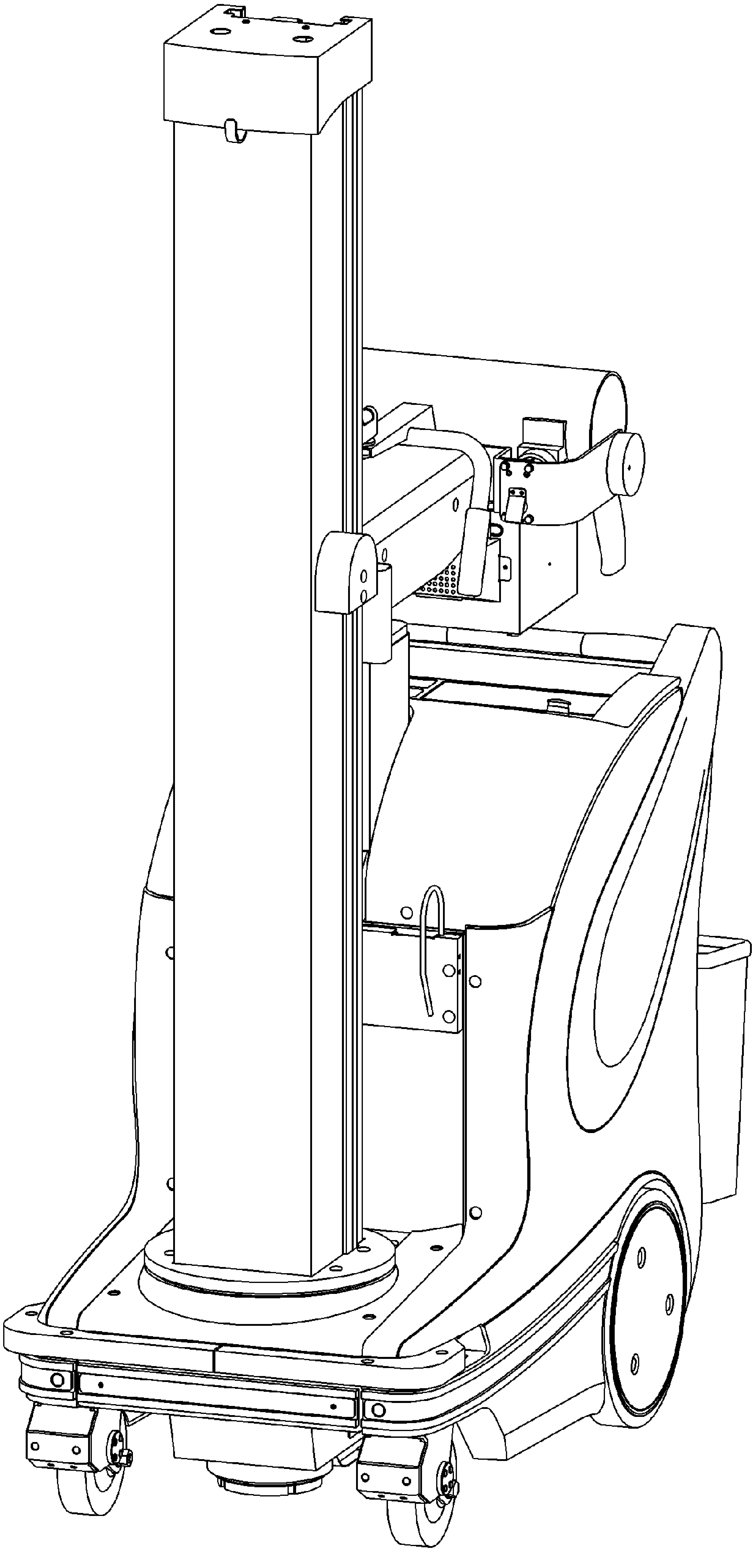


FIG. 9

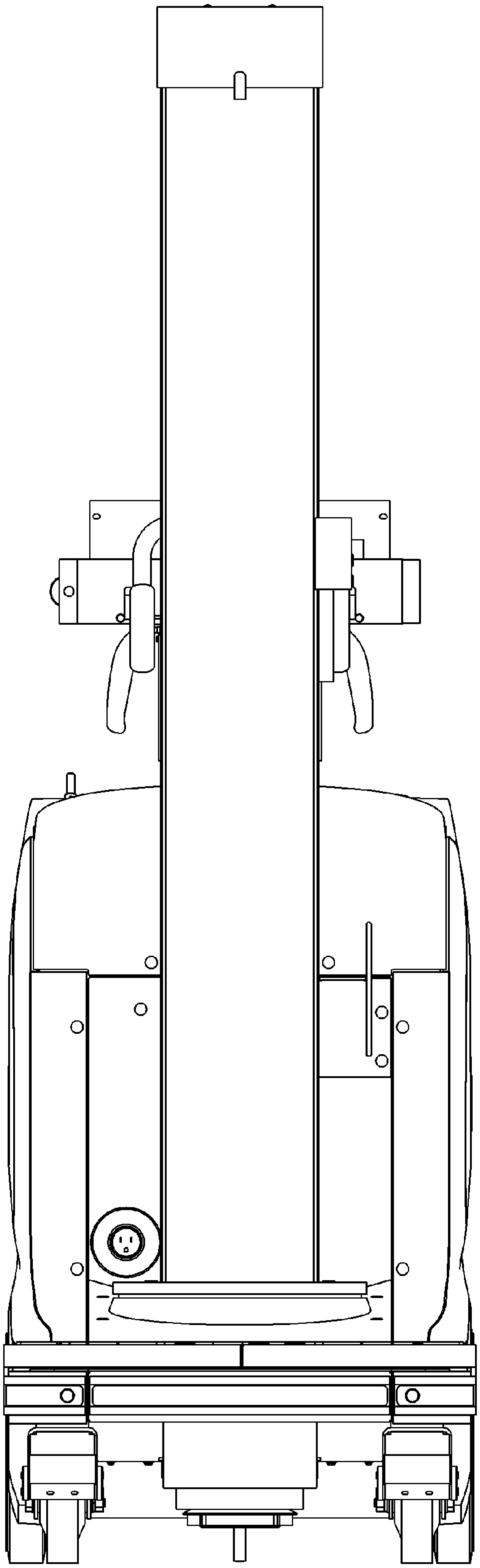


FIG. 10

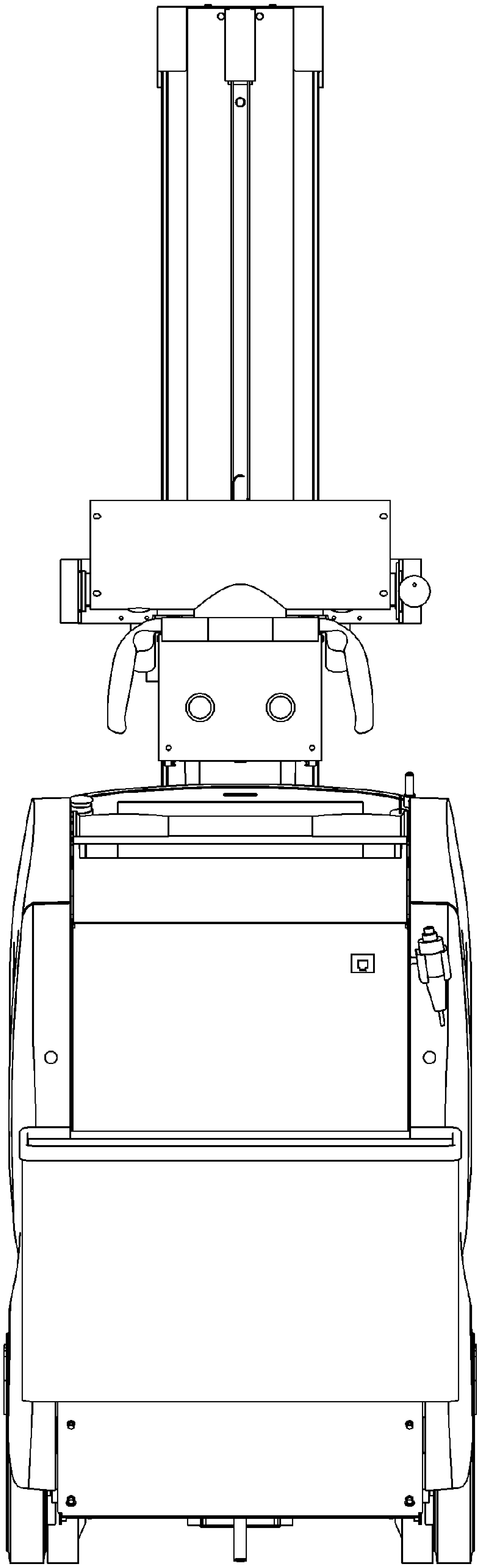


FIG. 11

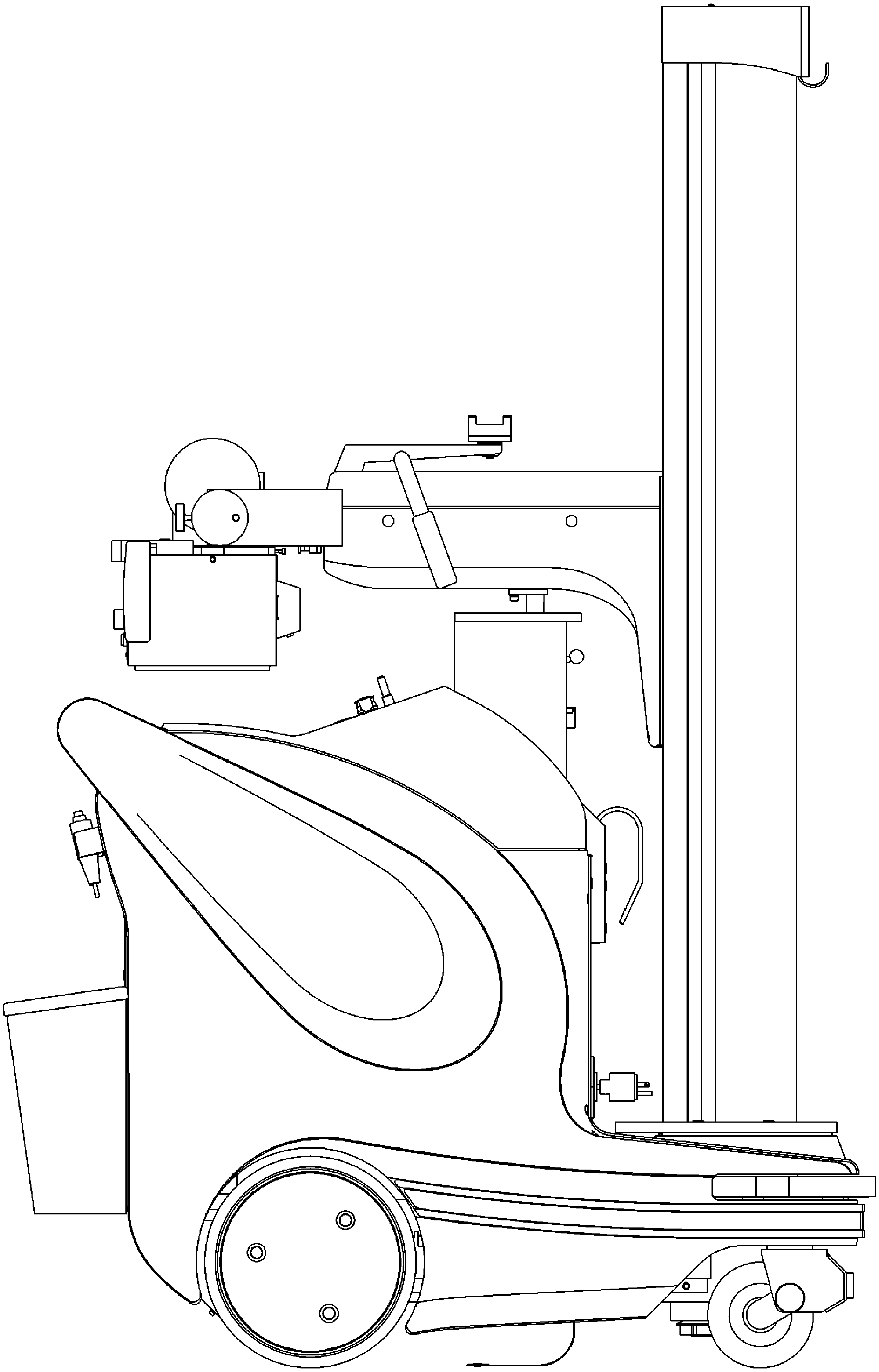


FIG. 12

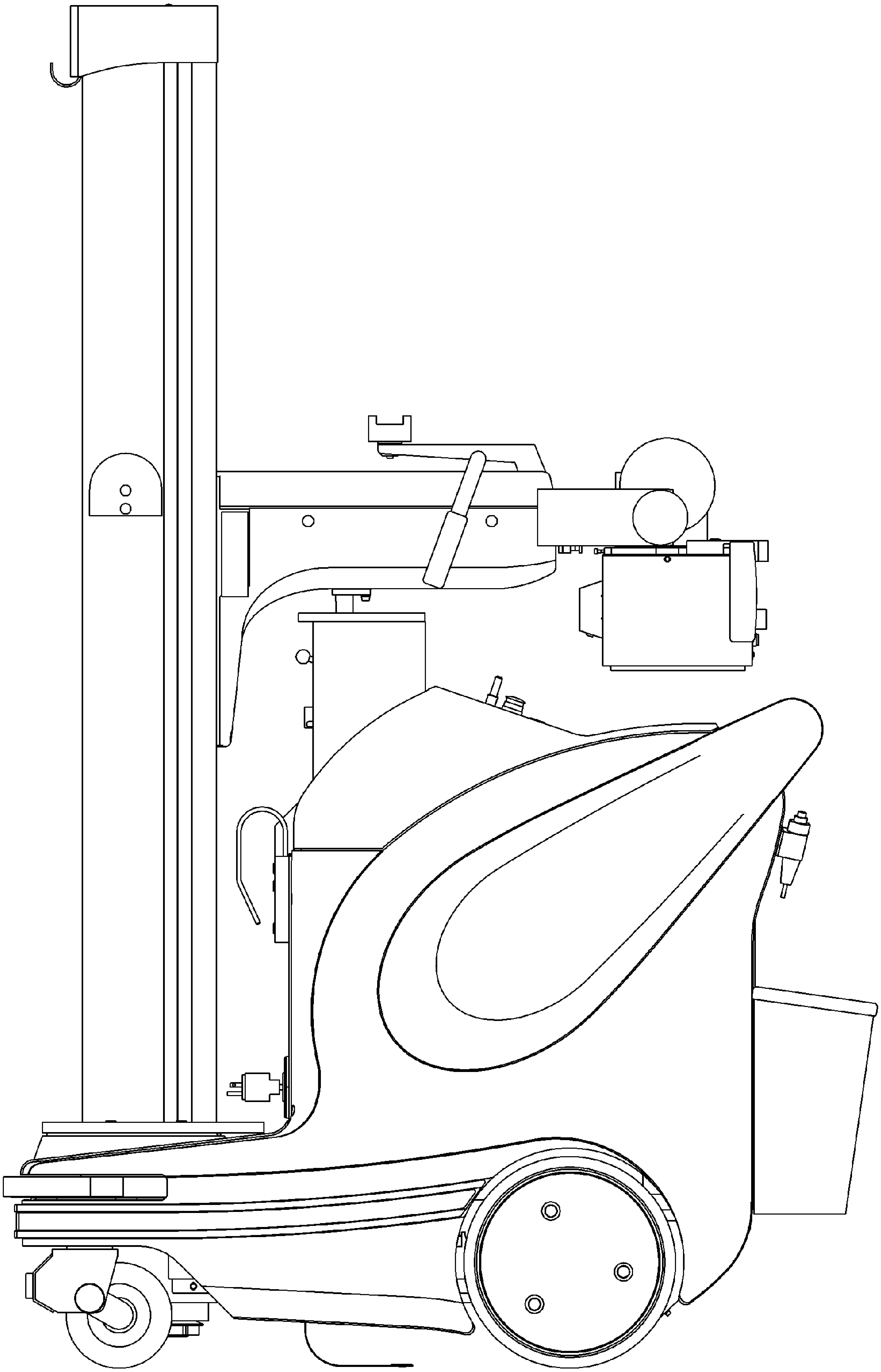


FIG. 13

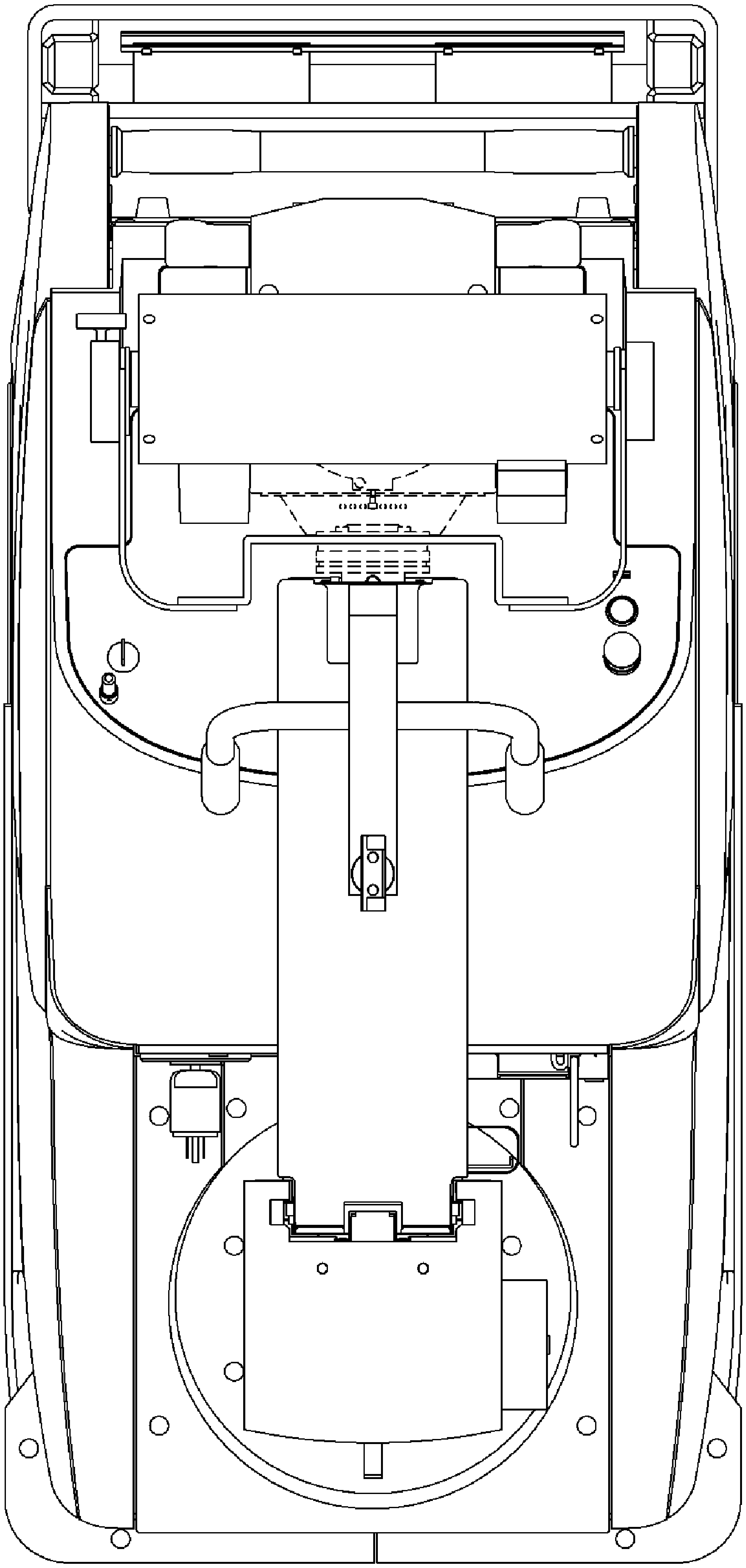


FIG. 14

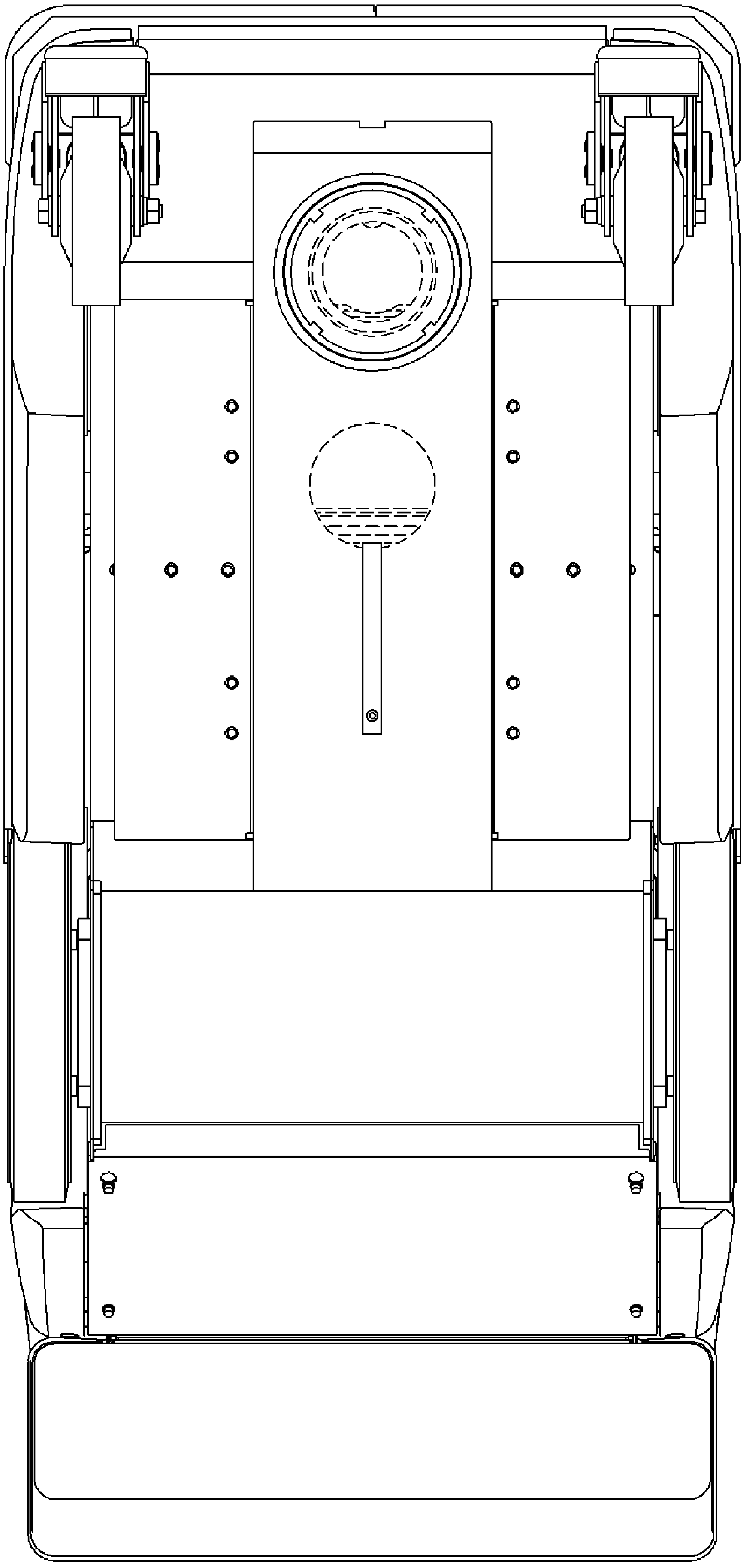


FIG. 15

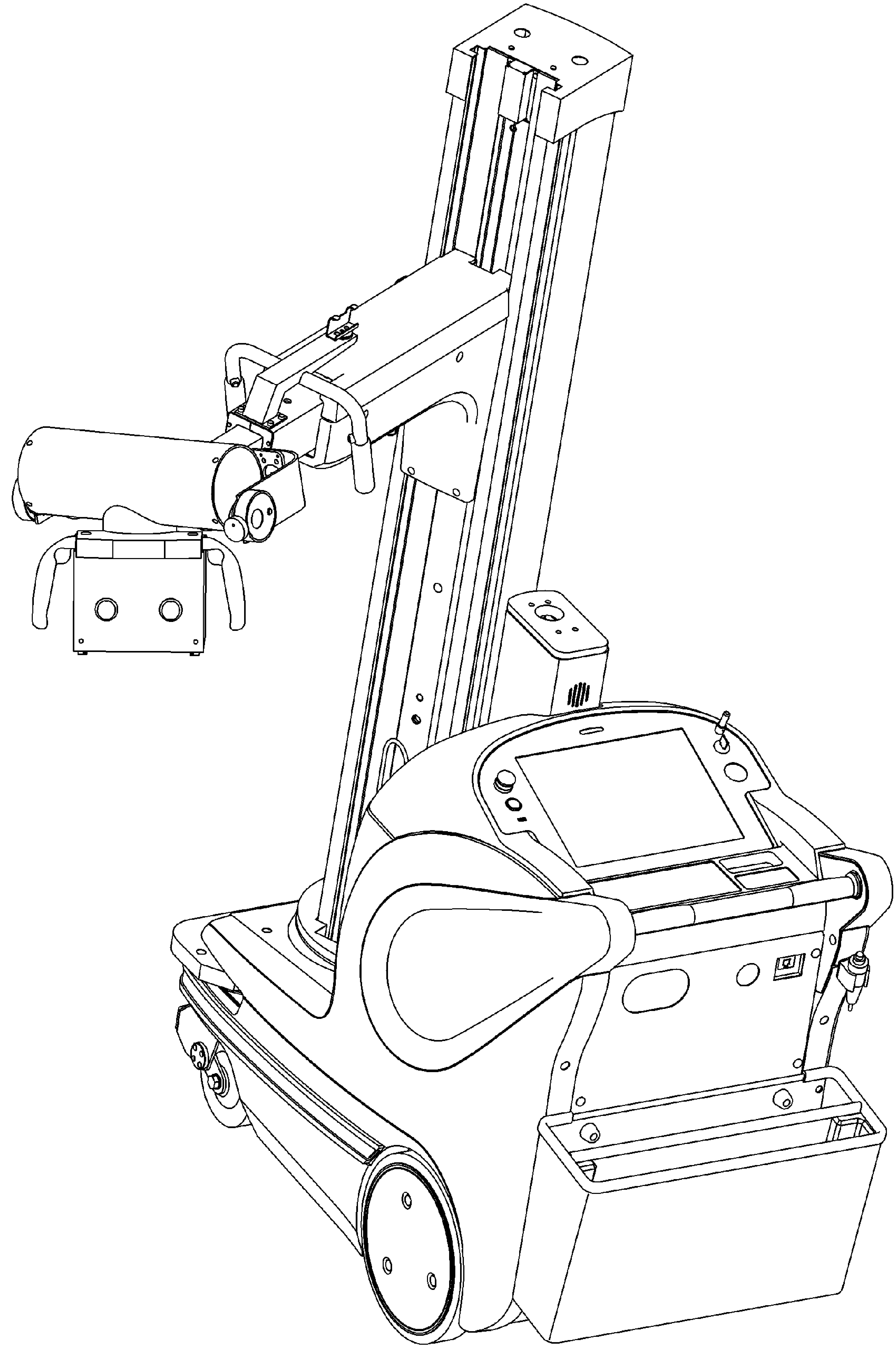


FIG. 16

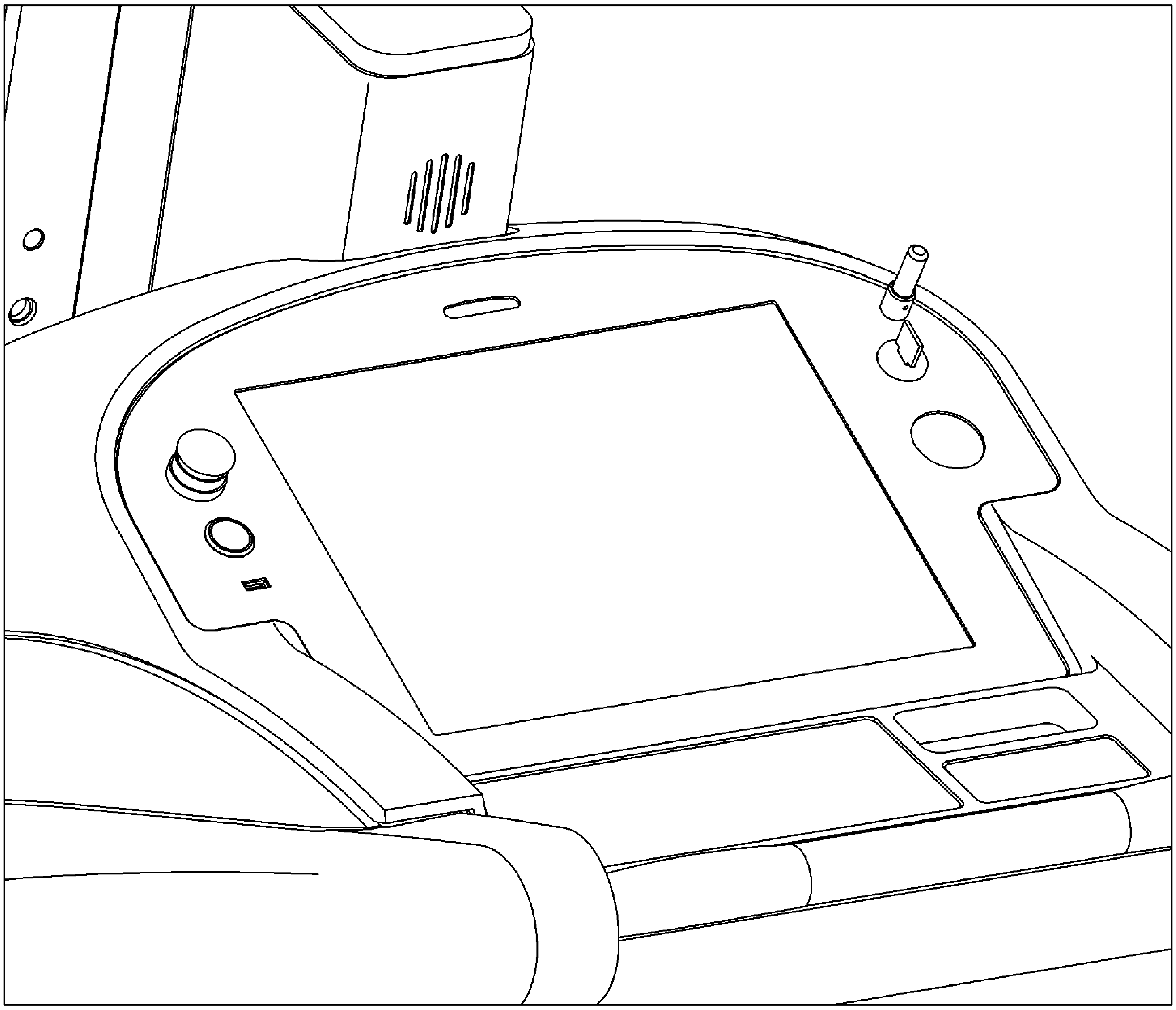


FIG. 17